

Features

• Split Gate Trench MOSFET technology

- Excellent package for heat dissipation
- High density cell design for low RDS(ON)

Product Summary

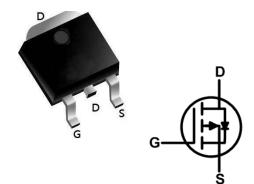


BVDSS	RDSON	ID
-100V	115mΩ	-15A

Applications

- Battery switching application
- Hard switched and high frequency circuits
- Power management

TO252-3L Pin Configuration



Absolute Maximum Ratings:

Symbol	Parameter	Value	Units	
V_{DSS}	Drain-to-Source Voltage	-100	V	
T	Continuous Drain Current	-15	A	
I_D	Continuous Drain Current	-9.2	A	
I_{DM}^{a1}	Pulsed Drain Current	-58	A	
V_{GS}	Gate-to-Source Voltage	±20	V	
P_{D}	Power Dissipation	69	W	
тт	Operating Junction and Storage Temperature		150 55 to 150	°C
T _J , T _{stg}	Range	150, -55 to 150		
$\mathrm{T_{L}}$	Maximum Temperature for Solder	ring	260	°C

Thermal Characteristics:

Symbol	Parameter	Value	Units
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	1.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	75	°C/W



Electrical Characteristics (TA= 25°C unless otherwise specified):

Static Ch	Static Characteristics							
Cymb ol	Parameter	T	Value			Units		
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units		
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_{D}=-250\mu A$	-100			V		
I_{DSS}	Drain to Source Leakage Current	V_{DS} =-100V, V_{GS} =0V			1	μΑ		
$I_{GSS(F)}$	Gate to Source Forward Leakage	V_{GS} =-20V, V_{DS} =0V			100	nA		
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS} = +20V, V_{DS} = 0V$			-100	nA		
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{D}=-250 \mu A$	-1.2	-1.7	-2.2	V		
R _{DS(ON)1}	Drain-to-Source On- Resistance	V_{GS} =-10V, I_{D} =-5A		115	150	mΩ		
R _{DS(ON)2}	Drain-to-Source On- Resistance	V_{GS} =-4.5V, I_{D} =-5A		130	165	mΩ		

Dynamic Characteristics								
Cyren le o l	Donomoton	Test Conditions	Value			TT '4		
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units		
C_{iss}	Input Capacitance	$V_{GS} = 0V$		700	1			
Coss	Output Capacitance	$V_{\rm DS} = -50 V$		56	1	pF		
C_{rss}	Reverse Transfer Capacitance	f = 1.0MHz		8.6				

Resistive Switching Characteristics							
Cymph ol	Do no martan	T		I Indian			
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units	
$t_{d(ON)}$	Turn-on Delay Time	$I_D = -5A$	-	5.9	-		
tr	Rise Time	$I_D = -5A$ $V_{DS} = -50V$		3.7		nc	
$t_{d(OFF)}$	Turn-Off Delay Time	$V_{GS} = -10V$	1	39.5	1	ns	
t_{f}	Fall Time	$R_G = 5\Omega$	1	24.6	1		
Q_{g}	Total Gate Charge	$V_{GS} = -10V$	1	12.7	-		
Q_{gs}	Gate Source Charge	$V_{\rm DS} = -50 V$	1	2.1	-	nC	
Q_{gd}	Gate Drain Charge	$I_D = -5A$	-	2.3			

Source-Drain Diode Characteristics								
Cymala al	Domomoton	T C. 1'.'	Value			TT:4		
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units		
V_{SD}	Diode Forward Voltage	$I_S=-5A$, $V_{GS}=0V$			-1.2	V		
t _{rr}	Reverse Recovery time	$I_{S}=-5A, V_{DD}=-50V$		66		ns		
Qrr	Reverse Recovery Charge	$dI/dt=100A/\mu s$		214		nC		

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature



Characteristics Curve:

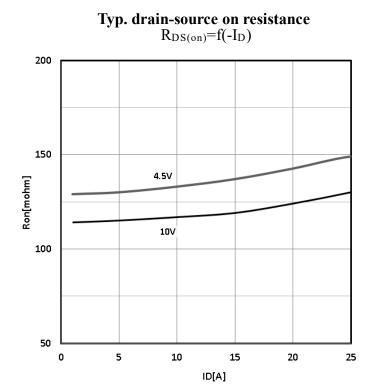
Typ. output characteristics $-I_D = f(-V_{DS})$ 50 40 40 30 20 10

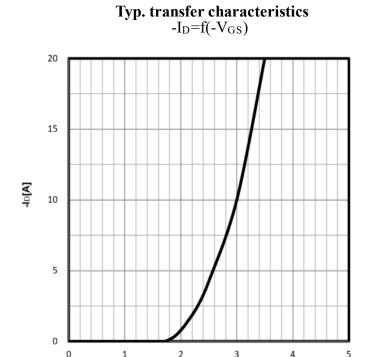
3

-Vps[V]

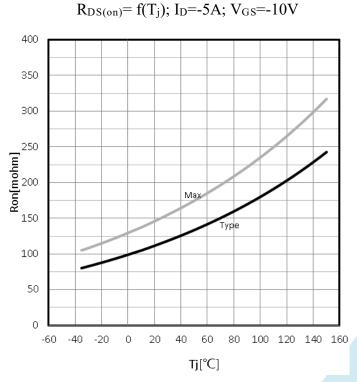
5

1





-Vgs[V]

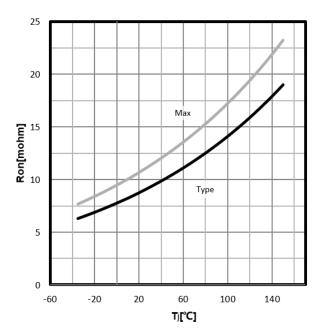


Drain-source on-state resistance

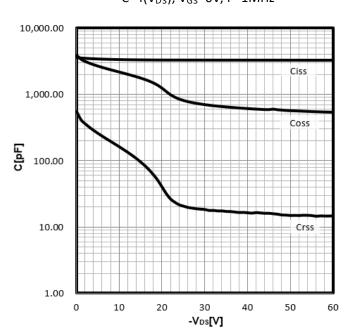


Drain-source on-state resistance

 $R_{DS(on)}$ =f(T_j); I_D =-20A; V_{GS} =-10V



Typ. capacitances C = f(V_{DS}); V_{GS}=0V; f =1MHz



Typ. gate charge V_{GS} =f(Q_{gate}); I_D =-20A

10

0

10

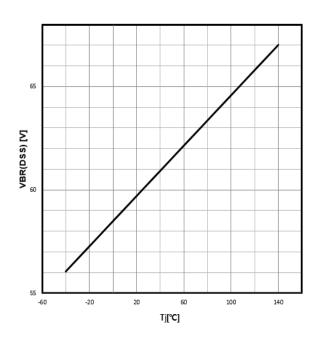
Q_g[nC] 30

50

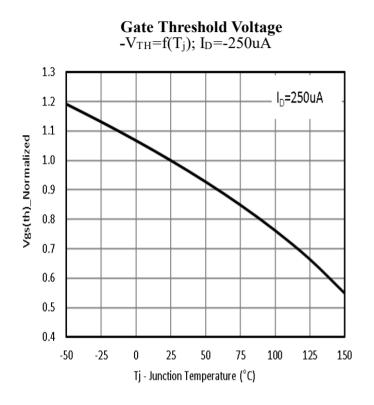
40

Drain-source breakdown voltage

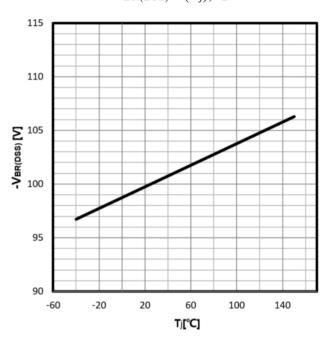
 $V_{BR(DSS)}=f(T_j); I_D=-250uA$

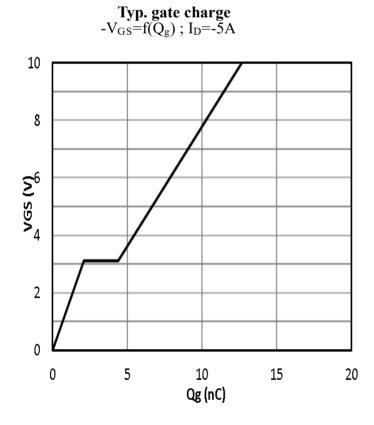


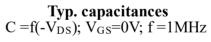


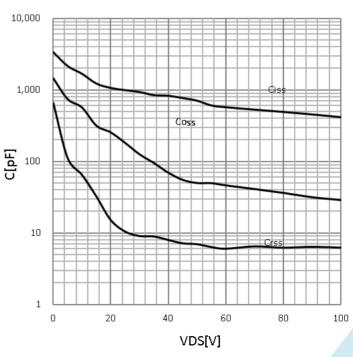


 $\begin{array}{c} \textbf{Drain-source breakdown voltage} \\ \textbf{-}V_{BR(DSS)} \!\!=\!\! f(T_j); \ I_D \!\!=\!\! -250 uA \end{array}$

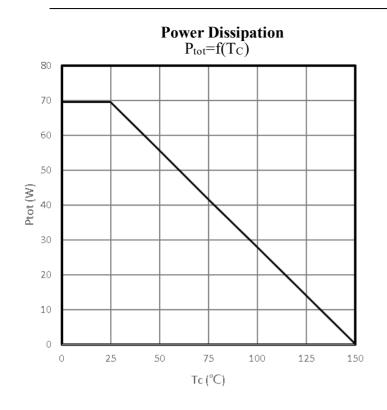


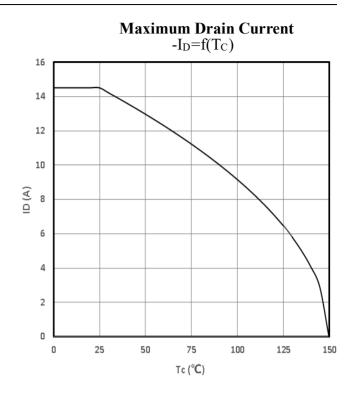


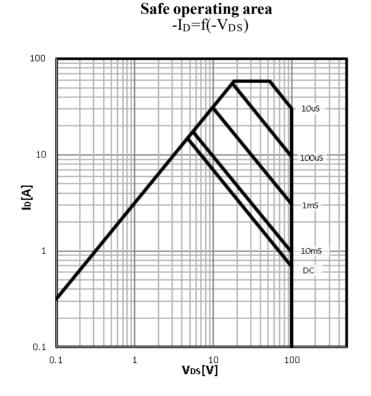


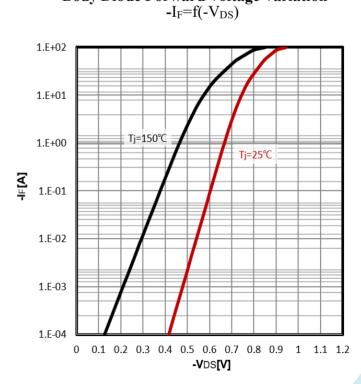








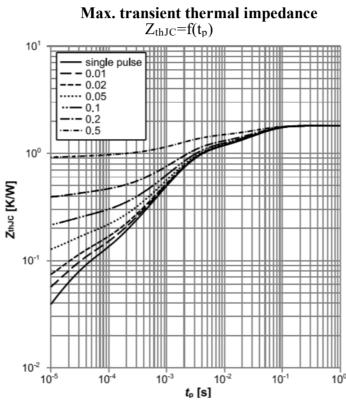




Body Diode Forward Voltage Variation



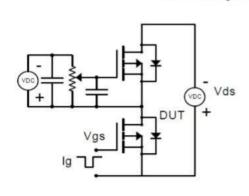


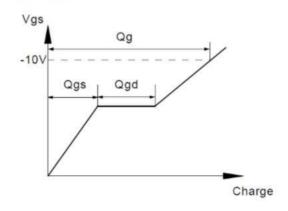




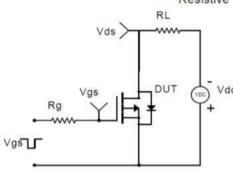
Test Circuit and Waveform:

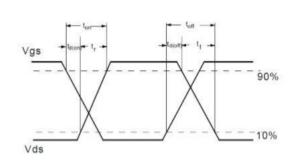
Gate Charge Test Circuit & Waveform



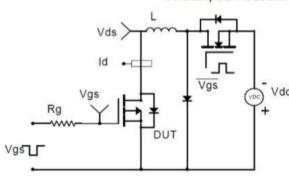


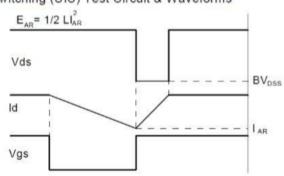
Resistive Switching Test Circuit & Waveforms



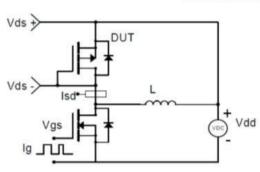


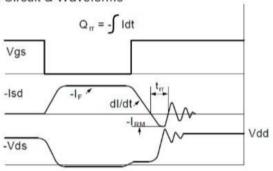
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





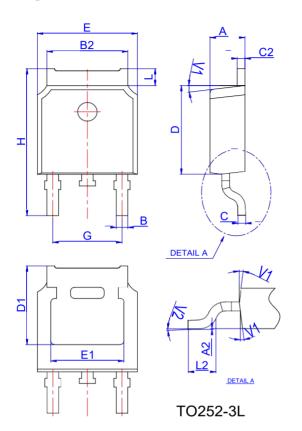
Diode Recovery Test Circuit & Waveforms





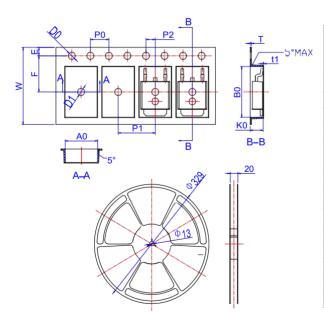


Package Mechanical Data TO252-3L



	Dimensions						
Ref.		Millimeter			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.	
Α	2.10		2.50	0.083		0.098	
A2	0		0.10	0		0.004	
В	0.66		0.86	0.026		0.034	
B2	5.18		5.48	0.202		0.216	
С	0.40		0.60	0.016		0.024	
C2	0.44		0.58	0.017		0.023	
D	5.90		6.30	0.232		0.248	
D1	5.30REF			().209REF		
E	6.40		6.80	0.252		0.268	
E1	4.63			0.182			
G	4.47		4.67	0.176		0.184	
Н	9.50		10.70	0.374		0.421	
L	1.09		1.21	0.043		0.048	
L2	1.35		1.65	0.053		0.065	
V1		7°			7°		
V2	0°		6°	0°		6°	

Reel Spectification-TO252-3L



	Dimensions						
Ref.		Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.	
W	15.90	16.00	16.10	0.626	0.630	0.634	
E	1.65	1.75	1.85	0.065	0.069	0.073	
F	7.40	7.50	7.60	0.291	0.295	0.299	
D0	1.40	1.50	1.60	0.055	0.059	0.063	
D1	1.40	1.50	1.60	0.055	0.059	0.063	
P0	3.90	4.00	4.10	0.154	0.157	0.161	
P1	7.90	8.00	8.10	0.311	0.315	0.319	
P2	1.90	2.00	2.10	0.075	0.079	0.083	
A0	6.85	6.90	7.00	0.270	0.271	0.276	
В0	10.45	10.50	10.60	0.411	0.413	0.417	
K0	2.68	2.78	2.88	0.105	0.109	0.113	
Т	0.24		0.27	0.009		0.011	
t1	0.10	·		0.004			
10P0	39.80	40.00	40.20	1.567	1.575	1.583	